| | | r | | |
|---------------------------|--------------------------------|----------|---------------------------------|--|
| Notic of R ferenc s Cit d | Application/Control No. Applic | | cant(s)/Patent Under | |
| | 09/943,148 | | Reexamination VAN DE VEN ET AL. | |
| Notic of R ferences of a | Examiner | Art Unit | | |
| | Norca L. Torres-Velazquez | 1771 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|-----------|---|--|-----------------|-----------------|----------------|
| | 4 | US-4,344,998 | 08-1982 | de Leeuw et al. | 428/212 |
| | В | US-5,458,955 | 10-1995 | Vaughn et al. | 428/212 |
| | С | US-6,187,696 | 02-2001 | Lim et al. | 442/77 |
| | ם | US-4,068,034 | 01-1978 | Segawa et al. | 428/421 |
| | E | US-4,637,947 | 01-1987 | Maekawa et al. | 428/68 |
| | F | US-5,447,783 | 09-1995 | Horn, Murray H. | 428/216 |
| | G | US- | | | |
| | Н | US- | | | |
| \square | _ | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | |
| | Ρ | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | τ | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | ٧ | |
| | w | |
| | Х | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.